

Data sheet acquired from Harris Semiconductor SCHS058C – Revised October 2003

# CD4076B Types

# CMOS 4-Bit D-Type Registers

High-Voltage Types (20-Volt Rating)

■ CD4076B types are four-bit registers consisting of D-type flip-flops that feature three-state outputs. Data Disable inputs are provided to control the entry of data into the flip-flops. When both Data Disable inputs are low, data at the D inputs are loaded into their respective flip-flops on the next positive transition of the clock input. Output Disable inputs are also provided. When the Output Disable inputs are both low, the normal logic states of the four outputs are available to the load. The outputs are disabled independently of the clock by a high logic level at either Output Disable input, and present a high impedance.

The CD4076B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

#### Features:

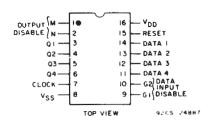
- Three-state outputs
- Input disabled without gating the clock
- Gated output control lines for enabling or disabling the outputs
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 μA at 18 V over full package temperature range; 100 nA at 18 V and 25°C
- Noise margin over full package temperature range:

1 V at V<sub>DD</sub> = 5 V

2 V at V<sub>DD</sub> = 10 V

2.5 V at VDD = 15 V

- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"



TERMINAL ASSIGNMENT

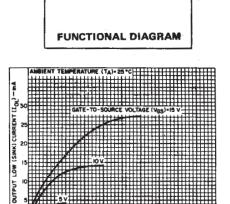
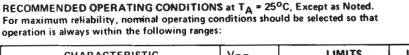


Fig.1 — Typical output low (sink) current characteristics.

DRAIN-TO-SOURCE VOLTAGE (Vns)-V



CHARACTERISTIC	V <sub>DD</sub>	L1N	LIMITS		
	(V)	Min.	Max.		
Supply Voltage Range (For TA=Full Package Temperature Range)		3	18	v	
	5	200			
Data Setup Time, ts	10	80		ns	
	15	60	m.ers		
	5	200	-		
Clock Pulse Width, tw	10	100		ns	
***	15	80	-	Li	
	5		3		
Clock Input Frequency, fc1	10	dc	6	MHz	
, , , , ,	15		8		
	5	-	15		
Clock Input Bise or Fall Time, trCL,tfCL	10	_	5	μs	
	15	] –	5		
	5	120	-		
Reset Pulse Width, tw	10	50	~-	ns	
, , , , , ,	15	40	·		
	5	180	-		
Data Input Disable Setup Time, t <sub>S</sub>	10	100	-	ns	
200	15	70	_		

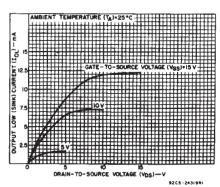


Fig.2 — Minimum output low (sink) current characteristics.

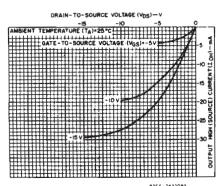


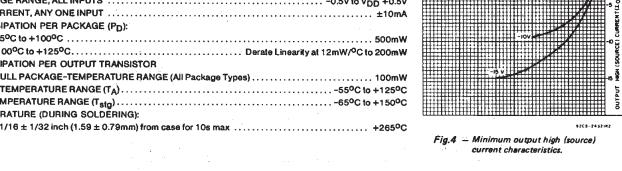
Fig.3 — Typical output high (source) current characteristics.

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## CD4076B Types

#### MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (VDD)	•
Voltages referenced to VSS Terminal)	0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS	
DC INPUT CURRENT, ANY ONE INPUT	
POWER DISSIPATION PER PACKAGE (PD):	
For T <sub>A</sub> = -55°C to +100°C	500mW
For T <sub>A</sub> = +100°C to +125°C	
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Type	s)100mW
OPERATING-TEMPERATURE RANGE (TA)	55°C to +125°C
STORAGE TEMPERATURE RANGE (Tsto)	65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):	
At distance 1/16 $\pm$ 1/32 inch (1.59 $\pm$ 0.79mm) from case for 10s max	+265°C



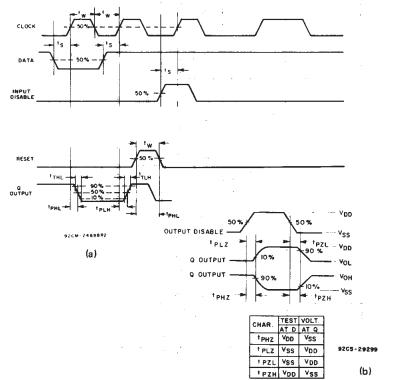


Fig.5 - Functional waveforms for CD40768.

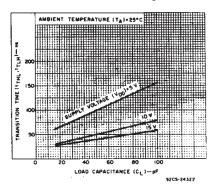


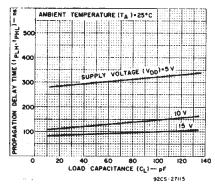
Fig.7 - Typical transition time vs. load capacitance.

Truth Table

		Di	Input sable	3. Data	Next State Output	
Reset	Clock	G1	G2	D	Q	
1 1	х	x	x	х	0	
0	0	Х	x	×	g	NC
0		1	х	×	a i	NC
0		×	1	×	٥	NC
0		0	0	1 -	-1	
0	/.	0	0	0 .	0	
0	1	х	х	х	Q	NC
0	_	×	x	×	a	NC

When either Output Disable M or N is high, the outputs are disabled (high impedance state), however sequential operation of the flip flops is not affected.

- 1 ≡ High Level 0 ≡ Low Level
- X = Don't Care



DRAIN-TO-SOURCE VOLTAGE (VDS)-V

Fig.6 - Typical propagation delay time vs. load capacitance (clock to Q).

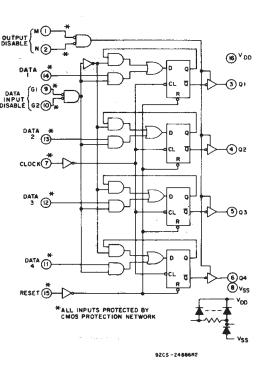


Fig.8 - CD4076B logic diagram.

DYNAMIC ELECTRICAL CHARACTERISTICS at  $T_A = 25^{\circ}$ C, input  $t_r, t_f = 20$  ns,  $C_L = 50$  pF,  $R_L = 200$  k $\Omega$  (Unless otherwise noted)

CHARACTERISTIC	TEST CONDI	TIONS		LIMITS			
		V <sub>DD</sub>	Min.	Тур.	Max.	,	
Propagation Delay Time: Clock to Q Output, tpHL, tpLH		5 10 15		300 125 90	600 250 180		
Reset, <sup>t</sup> PHL		5 10 15	٠.	230 100 75	460 200 150		
3-State Output 1 or 0 to High Impedance, IpHZ, IpLZ	R <sub>L</sub> = 1 kΩ	- <b>5</b> ∉ 10 15	ŧ	1 <b>50</b> 75 60	300 150 120	ns	
3-State High Impedance to 1 or 0 Output, tpZH, tpZL	R <sub>L</sub> = 1 kΩ	5 10 15		150 75 60	300 150 120	·	
Transition Time, t <sub>THL</sub> t <sub>TLH</sub>		5 10 15		100 50 40	200 100 80	ns	
Maximum Clock Input Frequency, f <sub>CL</sub>		5 10 15	3 6 8	6 12 16		MHz	
Minimum Clock Pulse Width, t <sub>W</sub>		5 10 15		100 50 40	200 100 80	ns	
Maximum Clock Input Rise or Fall Time, of Irol, Ifol		5 10 15	15 5 5	. 1 1 1	1 1 1	μs -	
Minimum Reset Pulse With, t <sub>W</sub>		5 10 15		60 25 20	120 50 40	ns	
Minimum Data Setup Time, t <sub>S</sub>		5 10 15		100 40 30	200 80 60	ns	
Minimum Data Input Disable Setup Time, t <sub>S</sub>		5 10 15	- - -	90 50 35	180 100 70	ns	
Input Capacitance, CIN	Any Input	<del>-</del> -		5	7.5	pF	

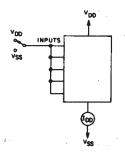


Fig.11 - Quiescent device current test circuit.

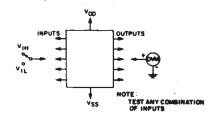


Fig. 12 - Input voltage test circuit.

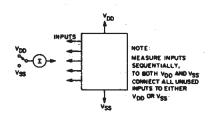


Fig. 13 - Input current test circuit.

### STATIC ELECTRICAL CHARACTERISTICS

CHARACTER-	CON	DITION	NS	LIMI	T\$ AT I	NDICAT	ED TE	MPER/			
ISTIC	Vo	VIN	VDD							UNITS	
	(v) :	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.	
Quiescent Device		0,5	5	5	5	150	150		0.04	5	I
Current,		0,10	10	10	10	300	300	-	0.04	10	
IDD Max.		0,15	15	20	20	600	600	r,	0.04	20	μΑ
	_	0,20	20	100	100	3000	3000	_	0.08	100	1
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	<b>1</b> –	
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	-	1
10L Min.	1.5	0,15	15	4.2	4	2.8	2.4	34	6.8		1
Output High	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	T -	mA
(Source) Current, IOH Min.	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-	1
	9.5	0,10	10	-1.6	-1.5	1.1	-0.9	-1.3	-2.6	-	1
	13.5	0,15	15	-4.2	-4	-2.8	-2.4	3.4	-6.8	_	ı
Output Voltage:		0,5	5,	0.05 -					0	0.05	
Low Level, VOL Max		0,10	10		,0	.05		_	0	0.05	V
VOL WAX	- **	0,15	15		0	.05			0	0.05	
Output Voltage:	_	0,5	5		4	95		4.95	5	-	
High-Level,	-	0,10	10		9	95		9.95	10	_	
VOH Min.		0,15	15		14	.95		14.95	15	_	1
Input Low	0.5, 4.5	_	5	1,5				_	T -	1.5	
Voltage,	1, 9	-	10		****	3			_	3	
VIL Max.	1.5,13.5	_	15		4				_	4	
Input High	0.5, 4.5		5	3.5				3.5	_	_	٧ .
Voltage,	1, 9	_	10			7		7		_	
VIH Min.	1.5,13.5	-	15		1	1		11		_	
Input Current IJN Max.		0,18	18	±0.1 ±0.1 ±1 ±1				_	±10 <sup>-5</sup>	±0.1	μΑ
3-State Output Leakage Current IOUT Max	0,18	0,18	18	±0.4	±0.4	±12	±12	_	±10-4	±0.4	μΑ

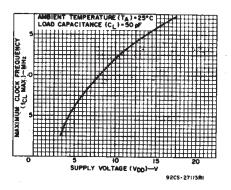


Fig.9 — Typical maximum clock input frequency vs. supply voltage.

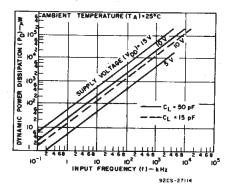
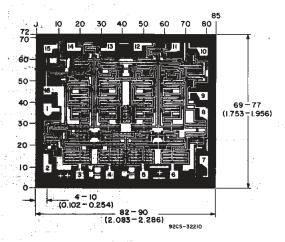


Fig. 10 — Typical dynamic power dissipation vs. frequency.



Dimensions and pad layout for CD4076BH

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils ( $10^{-3}$  inch).





6-Feb-2020

### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD4076BE	ACTIVE	PDIP	N	16	25	Green (RoHS & no Sb/Br)	NIPDAU	N / A for Pkg Type	-55 to 125	CD4076BE	Samples
CD4076BF	ACTIVE	CDIP	J	16	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	CD4076BF	Samples
CD4076BF3A	ACTIVE	CDIP	J	16	1	TBD	Call TI	N / A for Pkg Type	-55 to 125	CD4076BF3A	Samples
CD4076BM	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4076BM	Samples
CD4076BMT	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4076BM	Samples
CD4076BPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM076B	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet J\$709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



### PACKAGE OPTION ADDENDUM

6-Feb-2020

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#### OTHER QUALIFIED VERSIONS OF CD4076B, CD4076B-MIL:

Catalog: CD4076B

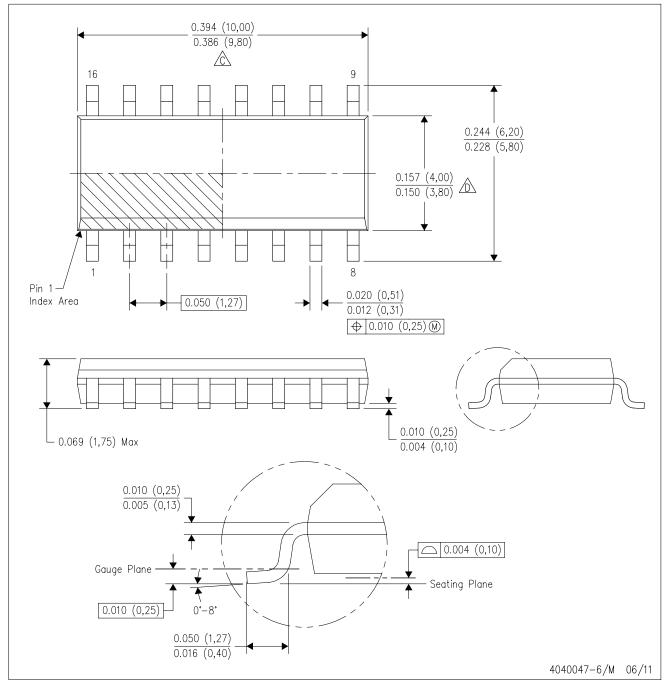
Military: CD4076B-MIL

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

# D (R-PDS0-G16)

### PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



# D (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



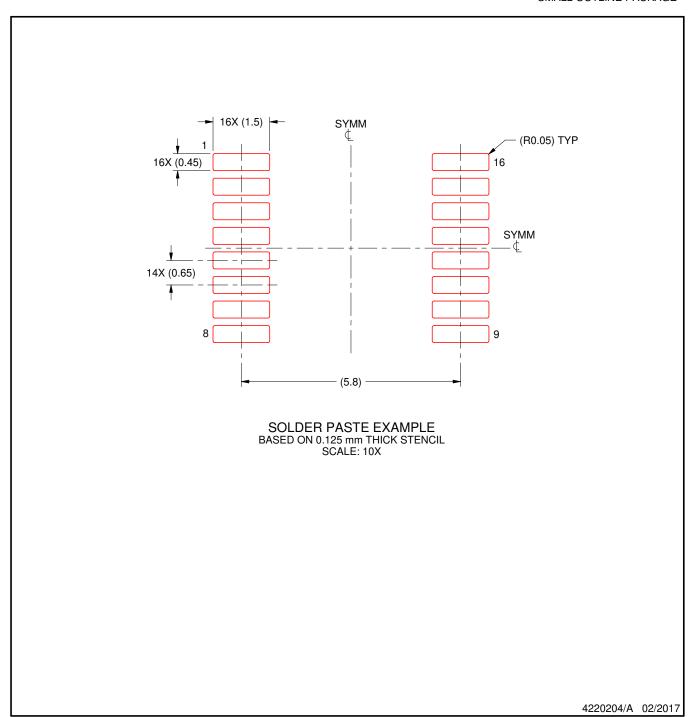
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



### 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

# N (R-PDIP-T\*\*)

## PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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